

Search Notes

Application/Control No.

09/965,772

Examiner

Quoc A. Tran

Applicant(s)/Patent under
Reexamination

AMANO, TOMIO

Art Unit

2176

SEARCHED


Class	Subclass	Date	Examiner
715	513	10/22/2005	<i>[Signature]</i>
715	523	10/22/2005	<i>[Signature]</i>
715	536	10/22/2005	<i>[Signature]</i>
707	4	10/22/2005	<i>[Signature]</i>
704	7	10/22/2005	<i>[Signature]</i>
715	501.1	4/9/2006	<i>[Signature]</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST(US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB DataBase) (see Search History Printout)	10/22/2005	<i>[Signature]</i>
IEEE DataBase (see search history printout)	10/22/2005	<i>[Signature]</i>
EAST(US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB DataBase) (see Search History Printout)	4/9/2006	<i>[Signature]</i>

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	09/865,772		AMANO, TOMIO	
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SEARCHED			
Class	Subclass	Date	Examiner
715	513 523 536	9/28/04	OT
704	7		
707	4		
345	173		
update above		5/16/05	OT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
INVENTOR SEARCH CHECK FOR double patent VS PAT. PHIS + IIC VS PG PUB, IBM-TDO FPO, SPO, DRLWANT update above	9/29/04 5/14/05	OT OT